

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No.10/323,525
Priority Filing DateDecember 18, 2002
Inventor Alan R. Reinberg
AssigneeMicron Technology, Inc.
Priority Group Art Unit 2824
Priority Examiner Christian D. Wilson
Attorney Docket No. MI22-2491
Title: Microelectronic Device Fabricating Methods, and Methods of Forming
a Pair of Field Effect Transistor Gate Lines of Different Base Widths From a
Common Deposited Conductive Layer

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 10/323,525, filed December 18, 2002. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. § 1.98(d) and MPEP § 609(2).

Citation of these references is respectfully requested.

Respectfully submitted,

Dated

1-27-04

By:



Mark S. Matkin
Reg. No. 32,268

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2491		SERIAL NO. PRIORITY 10/323,525	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Micron Technology, Inc.			
				FILING DATE PRIORITY December 18, 2002		GROUP PRIORITY 2824	

U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
AA	4,704,218	11/1987	Giammarco et al.	438	421		
AB	4,597,826	07/1986	Majima et al.	216	46		
AC	4,648,937	03/1987	Ogura et al.	438	702		
AD	4,857,477	08/1989	Kanamori	438	386		
AE	4,931,137	06/1990	Sibuet	216	13		
AF	5,618,383	04/1997	Randall	430	314		
AG	5,795,830	08/1998	Cronin et al.	438	696		
AH	5,895,740	04/1999	Chien et al.	430	313		
AI	6,103,596	08/2000	Peng	438	439		

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AJ							
AK							
AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AM		
	AN		
	AO		

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EL 979953368

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U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,103,613	08/2000	Akram	438	597	
	AB	6,140,227	10/2000	Chen et al.	438	644	
	AC	6,211,051 B1	04/2001	Jurgensen et al.	438	597	
	AD	6,232,229 B1	05/2001	Reinberg	438	669	
	AE	6,242,321 B1	06/2001	Acosta et al.	438	424	
	AF	6,509,626	01/2003	Reinberg	257	623	
	AG						
	AH						
	AI						

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